RMATION CITED BY APPLICANT THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

Applicant:

JUN 0 3 7005

R.M. Wasserman

Attorney Docket No. MEIP122366

Application No.: 10/808,948

Group Art Unit: 2625

Filed:

March 25, 2004

Examiner: Y.J. Couso

Title:

SYSTEM AND METHOD FOR EXCLUDING EXTRANEOUS FEATURES

FROM INSPECTION OPERATIONS PERFORMED BY A MACHINE

VISION INSPECTION SYSTEM

U.S. PATENT DOCUMENTS

*Examiner	Cite		Kind	Date	
<u>Initials</u>	No.	Document No.	Code	(mm/dd/yyyy)	Name
TR	U1	6,542,180	B1	04/01/2003	Wasserman et al.
TR	U2	6,627,863	B2	09/30/2003	Wasserman
TR	U3	2002/0076096	A1	06/20/2002	Silber et al.

FOREIGN PATENT DOCUMENTS

*Examiner Cite		17:	Publication Date		English	
Examine Cite		Kind	Fublication Date		Abstract	Translation
Initial No.	Document No.	Code	(mm/dd/yyyy)	Country	Provided	Provided

None.

OTHER INFORMATION (Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Initial	Cite No.	
TR	Ol	Brown, L.G., "A Survey of Image Registration Techniques" ACM Comp. Surv. 24(4):325-376, 1992.
TR	O2	Li, H., et al., "A Model-Based Approach for Automated Feature Extraction in Fundus Images," <i>Proceedings of the Ninth IEEE International Conference on Computer Vision</i> , Nice, France, October 13-16, 2003, Vol. 1, pp. 394 ff.

LAW OFFICES OF CHRISTENSEN O'CONNOR JOHNSON KINDNESS 1420 Fifth Avenue **Suite 2800** Seattle, Washington 98101 206.682.8100

*Examiner	Cite					
<u>Initial</u>	No.					
TR	О3		on Measuring Machine Operation Guide, Version 2.0,			
TR		Manual No. 4911GB, Series No. 359, Mitutoyo Corporation & Micro Encoder Inc., Kanagawa, Japan, September 1996.				
	O4	~	on Measuring Machine User's Guide, Version 7, 1st ed., 25A, Series No. 359, Mitutoyo Corporation & Micro			
mp.			wa, Japan, January 2003.			
TR	O5	Sasada, R., et al., "Stationary Grid Pattern Removal Using 2-Dimensional Technique for Moiré-Free Radiographic Image Display," Galloway, Robert L., Jr. (ed.), Visualization, Image-Guided Procedures, and Display, Proceedings of the SPIE - The International Society for Optical Engineering, Vol. 5029, San Diego, Calif., February 16-18, 2003, pp. 688-697.				
TR	O6	Shen, J., "Inpainting and the Fundamental Problem of Image Processing," SIA News 36(5):1-4, June 2003.				
Examiner /Thomas Redding/			Date Considered			
		omas Redding/	03/01/2007			

^{*}Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

GSF:lal